

<b>Notice of References Cited</b>	Application/Control No. 10/552,507	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner LOIS ZHENG	Art Unit 1793	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Crystallization of amorphous Zr-Ni alloys in the presence of H <sub>2</sub> , CO, O <sub>2</sub> , N <sub>2</sub> and argon gases", Aoki et al., Journal of Materials Science, Vol. 21 pages 793-798, 1986(Aoki)
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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